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# SIDC08D120F6

## Fast switching diode chip in EMCON-Technology

#### **FEATURES:**

- 1200V EMCON technology 120 μm chip
- soft, fast switching
- low reverse recovery charge
- small temperature coefficient

## This chip is used for:

EUPEC power modules and discrete devices



## **Applications:**

SMPS, resonant applications, drives

Chip Type	$V_R$	I <sub>F</sub>	Die Size	Package	Ordering Code
SIDC08D120F6	1200V	7A	2.2 x 3.7 mm <sup>2</sup>	sawn on foil	Q67050-A4169- A001

### **MECHANICAL PARAMETER:**

Raster size	2.2 x 3.7				
Area total / active	8.14 / 4.73	$mm^2$			
Anode pad size	2.98 x 1.48				
Thickness	120	μm			
Wafer size	150	mm			
Flat position	180	deg			
Max. possible chips per wafer	1850 pcs				
Passivation frontside	de Photoimide				
Anode metallisation	3200 nm AlSiCu				
Cathode metallisation  1400 nm Ni Ag –system suitable for epoxy and soft solder die bor					
Die bond	electrically conductive glue or solder				
Wire bond	AI, ≤500μm				
Reject Ink Dot Size	Ø 0.65mm ; max 1.2mm				
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C				



# SIDC08D120F6

## **Maximum Ratings**

Parameter	Symbol	Condition	Value	Unit
Repetitive peak reverse voltage	$V_{RRM}$		1200	V
Continuous forward current limited by	I <sub>F</sub>		7	
T <sub>jmax</sub>	/F		7	
Single pulse forward current	I <sub>ESM</sub>	$t_P = 10 \text{ ms sinusoidal}$	tbd	Α
(depending on wire bond configuration)	1 F 2 IVI	tp = 10 me emeeted	20	
Maximum repetitive forward current	1		14	1
limited by T <sub>jmax</sub>	I <sub>FRM</sub>		14	
Operating junction and storage temperature	$T_{\rm j}$ , $T_{ m stg}$		-55+150	°C

# $\textbf{Static Electrical Characteristics} \text{ (tested on chip)}, \ \textit{T}_{j}\text{=25 °C, unless otherwise specified}$

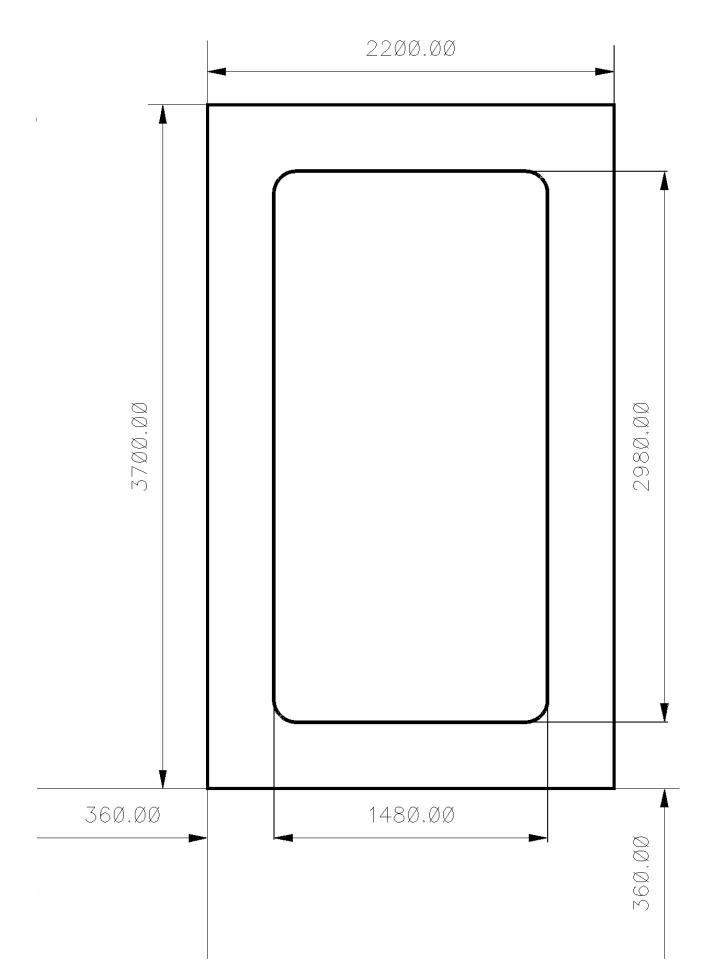
Parameter	Symbol	Cond	Value			Unit	
raiailietei	Syllibol	ymbol Conditions		min.	Тур.	max.	Oilit
Reverse leakage current	$I_{R}$	V <sub>R</sub> =1200V	$T_j=25^{\circ}C$			27	μΑ
Cathode-Anode breakdown Voltage	$V_{Br}$	I <sub>R</sub> =0.8mA	$T_j=25^{\circ}C$	1200			V
Forward voltage drop	$V_F$	I <sub>F</sub> =7A	$T_j=25^{\circ}C$		2.1		V

# **Dynamic Electrical Characteristics,** at $T_j$ = 25 °C, unless otherwise specified, tested at component

Parameter	Symbol	Symbol Conditions		Value			Unit
	Syllibol	Condi	Contaitions		Тур.	max.	7 """
Reverse recovery time	t <sub>rr1</sub>	$I_F=7A$	$T_j = 25 ^{\circ}C$		tbd		
	t <sub>rr2</sub>	$di/dt=A/\mu s$ $V_R=600V$	$T_j = 150 ^{\circ}C$				ns
Peak recovery current	I <sub>RRM1</sub>	I <sub>F</sub> =7A	$T_j = 25 ^{\circ}C$		tbd		_
	I <sub>RRM2</sub>	$di/dt = A/\mu s$ $V_R = 600V$	$T_j = 150 ^{\circ}C$				<sup>↑</sup>
Reverse recovery charge	Q <sub>rr1</sub>	I <sub>F</sub> =7A	<i>T<sub>j</sub></i> =25° <i>C</i>		tbd		nC
	Q <sub>rr2</sub>	$di/dt = A/\mu s$ $V_R = 600V$	$T_j = 150^{\circ} C$				
Peak rate of fall of reverse recovery current	di <sub>rr1</sub> /dt	I <sub>F</sub> =7A	<i>T</i> <sub>j</sub> = 25° <i>C</i>		tbd		A/μs
	di <sub>rr2</sub> /dt	$di/dt = A/\mu s$ $V_R = 600V$	$T_j = 150^{\circ} C$				
Softness	S1	$I_F = 7A$	$T_j=25^{\circ}C$		tbd		1
	S2	$di/dt = A/\mu s$ $V_R = 600V$	$T_j = 150^{\circ} C$				<u> </u>



# SIDC08D120F6





### Preliminary

# SIDC08D120F6

#### **FURTHER ELECTRICAL CHARACTERISTICS:**

This chip data sheet refers to the device data sheet line infine on technologies / EUPEC today today.

### **Description:**

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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